

Notice of References Cited	Application/Control No. 10/671,911	Applicant(s)/Patent Under Reexamination PARK, HEE-KEUN	
	Examiner Christopher Verdier	Art Unit 3745	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0146318 A1	10-2002	Hornig	415/204
	B	US-6,540,476 B2	04-2003	Huang et al.	416/185
	C	US-6,132,170 A	10-2000	Hornig	415/178
	D	US-5,954,124 A	09-1999	Moribe et al.	361/695
	E	US-6,688,379 B2	02-2004	Huang et al.	361/697
	F	US-6,637,501 B2	10-2003	Lin et al.	361/697
	G	US-6,568,907 B2	05-2003	Hornig et al.	416/185
	H	US-6,568,905 B2	05-2003	Hornig et al.	415/206
	I	US-6,643,129 B2	11-2003	Fujiwara	361/687
	J	US-5,044,887 A	09-1991	Duthie et al.	416/223B
	K	US-6,511,289 B2	01-2003	Yu	415/206
	L	US-6,206,641 B1	03-2001	Park et al.	416/182
	M	US-5,044,887 A	09-1991	Duthie et al.	416/223B

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-6-104,584-A	04-1994	Japan		361/695
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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